


<b>Search Notes</b>  	<b>Application/Control No.</b>  10777470	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  Mui, Christine T	<b>Art Unit</b>  1709

SEARCHED			
Class	Subclass	Date	Examiner
204	450	07.11.2007	CTM
366	341	07.11.2007	CTM
422	100, 101	07.11.2007	CTM
435	287.3	07.11.2007	CTM
436	052	07.11.2007	CTM
516	073	07.30.2007	CTM

SEARCH NOTES		
Search Notes	Date	Examiner
See EAST Search Report	07.10.2007	CTM

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner